

<b>Notice of References Cited</b>	Application/Control No. 10/827,534	Applicant(s)/Patent Under Reexamination ISHIKAWA, AKIRA	
	Examiner Belur V. Keshavan	Art Unit 2823	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0023448	02-2004	Fukunaga, Takeshi	438/149
	B	US-2005/0017303	01-2005	Ishikawa, Akira	257/347
	C	US-2005/0009252	01-2005	Yamazaki et al.	438/151
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Badih El-Kareh, "Introduction to VLSI Silicon Devices, Physics, Technology and Characterization" 1986, Kluwer Academic Press PP 66-67.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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